X-View2 Software Development Kit

X-View2 Software Development Kit is software for controlling all the digital platform detectors of DT. It provides easy-to-use and easy-to-learn user interface for detector controlling and image grabbing. X-View2 application software supports multi-detector and multi-view systems.

Multiple image enhancement functions of X-View2 enable fast and easy processing of the grabbed images. Simplified automatic troubleshooting procedure significantly shortens the time needed for equipment maintenance.

HIGHLIGHTS
- Control detector parameters
- Grab image data from the detector
- Processing and analyzing of grabbed images
- Multi-detector and multi-view support
- Enhanced image analysis tools
- Automatic troubleshooting procedure
- Dual-energy algorithms
- Advanced non-linear calibration
- Working modes:
  - Gigabit Ethernet
  - Camera link

X-VIEW2 SDK INCLUDES
- X-View2 software
- X-Lib demonstration software with source code
- X-Lib software library

SUPPORTED DT DETECTOR SUBSYSTEMS
- X-GCU and Digital X-cards
- X-Scan Series
KEY FEATURES

Detector configuration
- Easy to set detector module configuration in each X-GCU channel
- Set gain values and test pattern mode of each detector module
- Read properties of detector modules

Image analysis
- Pixel analysis for rows and columns
- Noise and average values
- Minimum and maximum values

Dual-energy process
- Two dual-energy combination methods that adopt different algorithms
- Based on effective atomic number ($Z_{eff}$) or on contrast differences

Troubleshooting
- Automated troubleshooting procedure
- View detector information
- Analyze offset image
- Analyze air-scan image
- Analyze corrected image
- Automatic generation of diagnostics report, including sample images

Health check
- Voltage, humidity and temperature check of each X-GCU control unit and Digital X-Card detector modules

SYSTEM REQUIREMENTS

Supported operating systems: Windows7/8.1 (32/64-bit), Ubuntu12.04 (32/64-bits)